

PATENT NUMBER

U.S. UTILITY Patent Application

PATENT DATE

APPLICATION NO.
09/955517

CONT/PRIOR

CLASS

SUBCLASS

ART UNIT

EXAMINER

216 TS6

599

1746

Hassanzadeh

APPLICANTS

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TITLE

In-situ or ex-situ profile monitoring of phase openings on
alternating phase shifting masks by scatterometryPTO-2040
12/99

CROSS REFERENCE(S)

CLASS (ONE SUBCLASS PER BLOCK)

☐ Continued on Issue Slip inside File Jacket

DRAWINGS

CLAIMS ALLOWED

Drawings

Figs. Drwg.

Print Fig.

Total Claims

Print Claim for O.G.

NOTICE OF ALLOWANCE MAILED

(Assistant Examiner)

(Date)

ISSUE FEE

Amount Due

Date Paid

(Primary Examiner)

(Date)

ISSUE BATCH NUMBER

(Legal Instruments Examiner)

(Date)

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